Search Notes



Applicant(s)/Patent under Reexamination

10/649,402

DYER ET AL.
Art Unit

Examiner

2817

Khanh V. Nguyen

SEARCHED					
Class	Subclass	Date	Examiner		
330	9	11/16/2004	NKV		
330	253	11/16/2004	NKV		
330	258	11/16/2004	NKV		
330	259	11/16/2004	NKV		
330	260	11/16/2004	NKV		
330	261	4/14/2005	NKV		
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
ABOVE	4/14/2005	NKV			
	•				
	Subclass	Subclass Date			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	4/14/2005	NKV		